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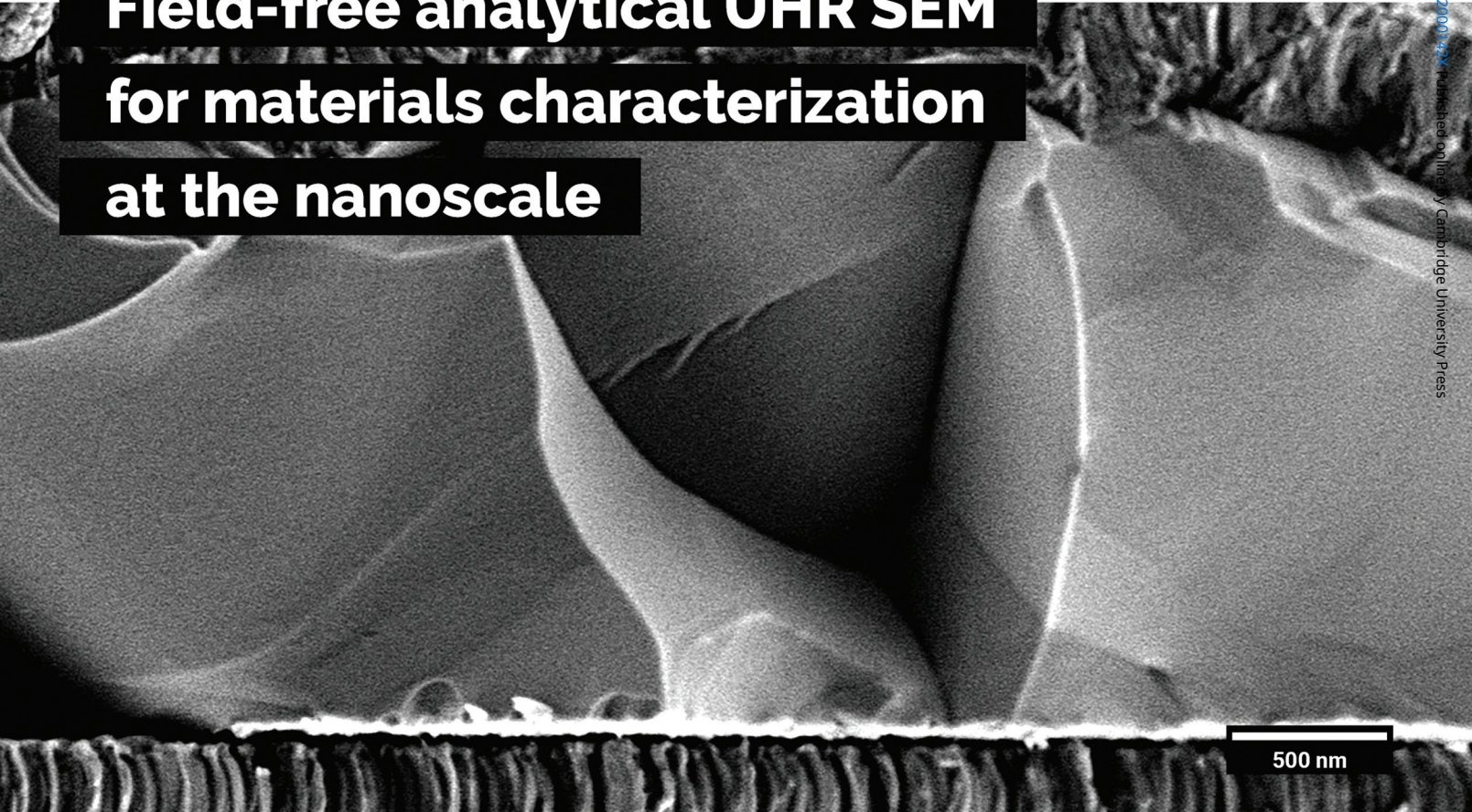
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500 nm

Fracture of solar cell, imaged at 2 keV, E-T detector
Sample courtesy of Center for Solar Energy and Hydrogen Research Baden-Württemberg, Stuttgart

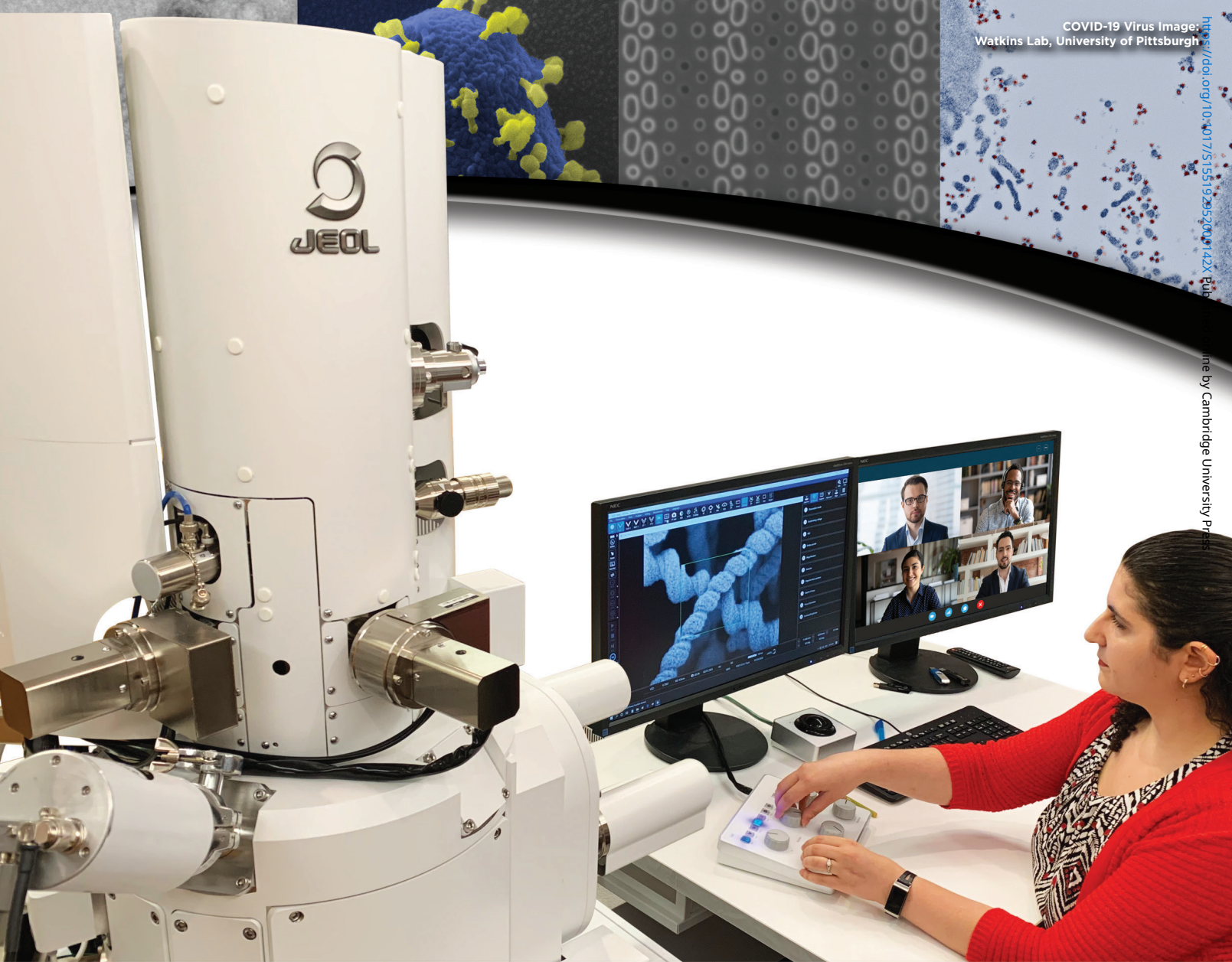
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